

WARP2 SERIES IGBT WITH
ULTRAFAST SOFT RECOVERY DIODE

Applications

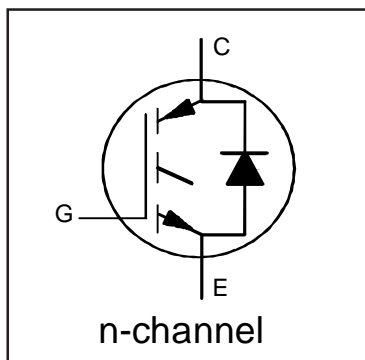
- Telecom and Server SMPS
- PFC and ZVS SMPS Circuits
- Uninterruptable Power Supplies
- Consumer Electronics Power Supplies
- Lead-Free

Features

- NPT Technology, Positive Temperature Coefficient
- Lower $V_{CE(SAT)}$
- Lower Parasitic Capacitances
- Minimal Tail Current
- HEXFRED Ultra Fast Soft-Recovery Co-Pack Diode
- Tighter Distribution of Parameters
- Higher Reliability

Benefits

- Parallel Operation for Higher Current Applications
- Lower Conduction Losses and Switching Losses
- Higher Switching Frequency up to 150kHz



$$V_{CES} = 600V$$

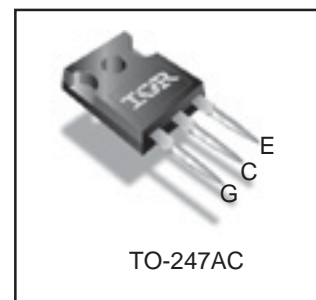
$$V_{CE(on)} \text{ typ.} = 2.00V$$

$$@ V_{GE} = 15V \quad I_C = 33A$$

Equivalent MOSFET Parameters①

$$R_{CE(on)} \text{ typ.} = 61m\Omega$$

$$I_D \text{ (FET equivalent)} = 50A$$

**Absolute Maximum Ratings**

	Parameter	Max.	Units
V_{CES}	Collector-to-Emitter Voltage	600	V
$I_C @ T_C = 25^\circ C$	Continuous Collector Current	75	A
$I_C @ T_C = 100^\circ C$	Continuous Collector Current	42	
I_{CM}	Pulse Collector Current (Ref. Fig. C.T.4)	150	
I_{LM}	Clamped Inductive Load Current ②	150	
$I_F @ T_C = 25^\circ C$	Diode Continuous Forward Current	50	
$I_F @ T_C = 100^\circ C$	Diode Continuous Forward Current	25	
I_{FRM}	Maximum Repetitive Forward Current ③	100	
V_{GE}	Gate-to-Emitter Voltage	± 20	V
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	370	W
$P_D @ T_C = 100^\circ C$	Maximum Power Dissipation	150	
T_J	Operating Junction and	-55 to +150	°C
T_{STG}	Storage Temperature Range		
	Soldering Temperature for 10 sec.	300 (0.063 in. (1.6mm) from case)	
	Mounting Torque, 6-32 or M3 Screw	10 lbf-in (1.1 N-m)	

Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$ (IGBT)	Thermal Resistance Junction-to-Case-(each IGBT)	—	—	0.34	°C/W
$R_{\theta JC}$ (Diode)	Thermal Resistance Junction-to-Case-(each Diode)	—	—	0.64	
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink (flat, greased surface)	—	0.50	—	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (typical socket mount)	—	—	40	
	Weight	—	6.0 (0.21)	—	g (oz)

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions	Ref.Fig
V _{(BR)CES}	Collector-to-Emitter Breakdown Voltage	600	—	—	V	V _{GE} = 0V, I _C = 500μA	
ΔV _{(BR)CES} /ΔT _J	Temperature Coeff. of Breakdown Voltage	—	0.61	—	V/°C	V _{GE} = 0V, I _C = 1mA (25°C-125°C)	
R _G	Internal Gate Resistance	—	1.2	—	Ω	1MHz, Open Collector	
V _{CE(on)}	Collector-to-Emitter Saturation Voltage	—	2.0	2.2	V	I _C = 33A, V _{GE} = 15V	4, 5, 6, 8, 9
		—	2.4	2.6		I _C = 50A, V _{GE} = 15V	
		—	2.6	2.9		I _C = 33A, V _{GE} = 15V, T _J = 125°C	
		—	3.2	3.6		I _C = 50A, V _{GE} = 15V, T _J = 125°C	
V _{GE(th)}	Gate Threshold Voltage	3.0	4.0	5.0	V	I _C = 250μA	7, 8, 9
ΔV _{GE(th)} /ΔT _J	Threshold Voltage temp. coefficient	—	-7.07	—	mV/°C	V _{CE} = V _{GE} , I _C = 1.0mA	
g _{fe}	Forward Transconductance	—	42	—	S	V _{CE} = 50V, I _C = 33A, PW = 80μs	
I _{CES}	Collector-to-Emitter Leakage Current	—	5.0	500	μA	V _{GE} = 0V, V _{CE} = 600V	
		—	1.0	—	mA	V _{GE} = 0V, V _{CE} = 600V, T _J = 125°C	
V _{FM}	Diode Forward Voltage Drop	—	1.3	1.7	V	I _F = 25A, V _{GE} = 0V	10
		—	1.5	2.0		I _F = 50A, V _{GE} = 0V	
		—	1.3	1.7		I _F = 25A, V _{GE} = 0V, T _J = 125°C	
I _{GES}	Gate-to-Emitter Leakage Current	—	—	±100	nA	V _{GE} = ±20V, V _{CE} = 0V	

Switching Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions	Ref.Fig		
Q _g	Total Gate Charge (turn-on)	—	240	360	nC	I _C = 33A	17		
Q _{gc}	Gate-to-Collector Charge (turn-on)	—	41	82		V _{CC} = 400V	CT1		
Q _{ge}	Gate-to-Emitter Charge (turn-on)	—	84	130		V _{GE} = 15V			
E _{on}	Turn-On Switching Loss	—	360	590	μJ	I _C = 33A, V _{CC} = 390V	CT3		
E _{off}	Turn-Off Switching Loss	—	380	420		V _{GE} = +15V, R _G = 3.3Ω, L = 210μH			
E _{total}	Total Switching Loss	—	740	960		T _J = 25°C ④			
t _{d(on)}	Turn-On delay time	—	34	44	ns	I _C = 33A, V _{CC} = 390V	CT3		
t _r	Rise time	—	26	36		V _{GE} = +15V, R _G = 3.3Ω, L = 210μH			
t _{d(off)}	Turn-Off delay time	—	130	140		T _J = 25°C ④			
t _f	Fall time	—	43	56	μJ	I _C = 33A, V _{CC} = 390V	CT3		
E _{on}	Turn-On Switching Loss	—	610	880		V _{GE} = +15V, R _G = 3.3Ω, L = 210μH		11, 13	
E _{off}	Turn-Off Switching Loss	—	460	530		T _J = 125°C ④		WF1, WF2	
E _{total}	Total Switching Loss	—	1070	1410	ns	I _C = 33A, V _{CC} = 390V	CT3		
t _{d(on)}	Turn-On delay time	—	33	43		V _{GE} = +15V, R _G = 3.3Ω, L = 200μH		12, 14	
t _r	Rise time	—	26	36		T _J = 125°C ④		WF1, WF2	
t _{d(off)}	Turn-Off delay time	—	140	160	pF	V _{GE} = 0V	16		
t _f	Fall time	—	50	65		V _{CC} = 30V			
C _{ies}	Input Capacitance	—	4750	—		f = 1Mhz			
C _{oes}	Output Capacitance	—	390	—	pF	V _{GE} = 0V, V _{CE} = 0V to 480V	15		
C _{res}	Reverse Transfer Capacitance	—	58	—					
C _{oes eff.}	Effective Output Capacitance (Time Related) ⑤	—	280	—					
C _{oes eff. (ER)}	Effective Output Capacitance (Energy Related) ⑤	—	190	—		T _J = 150°C, I _C = 150A	3		
RBSOA	Reverse Bias Safe Operating Area	FULL SQUARE						V _{CC} = 480V, V _p = 600V	CT2
						R _G = 22Ω, V _{GE} = +15V to 0V			
t _{rr}	Diode Reverse Recovery Time	—	50	75	ns	T _J = 25°C I _F = 25A, V _R = 200V,	19		
		—	105	160		T _J = 125°C di/dt = 200A/μs			
Q _{rr}	Diode Reverse Recovery Charge	—	112	375	nC	T _J = 25°C I _F = 25A, V _R = 200V,	21		
		—	420	4200		T _J = 125°C di/dt = 200A/μs			
I _{rr}	Peak Reverse Recovery Current	—	4.5	10	A	T _J = 25°C I _F = 25A, V _R = 200V,	19, 20, 21, 22		
		—	8.0	15		T _J = 125°C di/dt = 200A/μs		CT5	

Notes:

① R_{CE(on)} typ. = equivalent on-resistance = V_{CE(on)} typ. / I_C, where V_{CE(on)} typ. = 2.00V and I_C = 33A. I_D (FET Equivalent) is the equivalent MOSFET I_D rating @ 25°C for applications up to 150kHz. These are provided for comparison purposes (only) with equivalent MOSFET solutions.

② V_{CC} = 80% (V_{CES}), V_{GE} = 20V, L = 28 μH, R_G = 22 Ω.

③ Pulse width limited by max. junction temperature.

④ Energy losses include "tail" and diode reverse recovery, Data generated with use of Diode 30ETH06.

⑤ C_{oes eff.} is a fixed capacitance that gives the same charging time as C_{oes} while V_{CE} is rising from 0 to 80% V_{CES}.

C_{oes eff. (ER)} is a fixed capacitance that stores the same energy as C_{oes} while V_{CE} is rising from 0 to 80% V_{CES}.

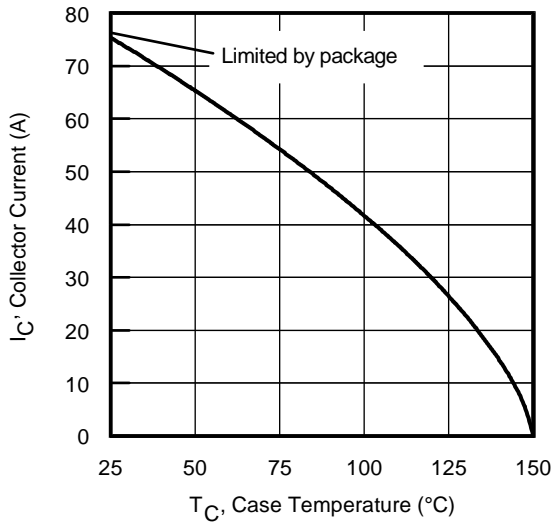


Fig. 1 - Maximum DC Collector Current vs. Case Temperature

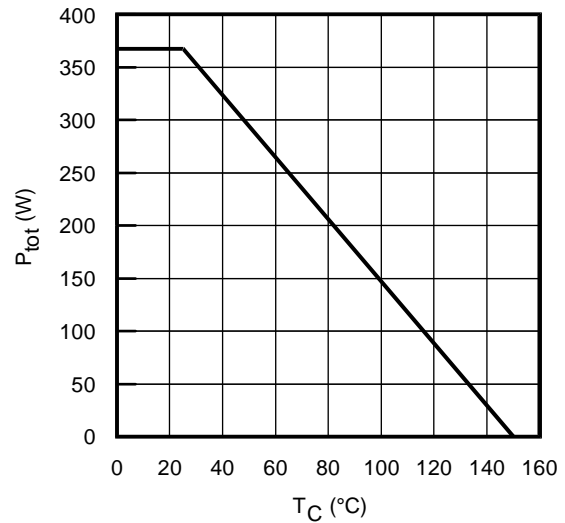


Fig. 2 - Power Dissipation vs. Case Temperature

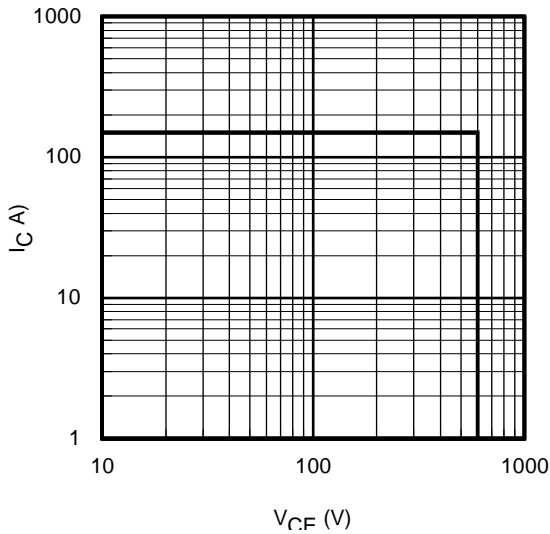


Fig. 3 - Reverse Bias SOA
 $T_J = 150^{\circ}\text{C}$; $V_{GE} = 15\text{V}$

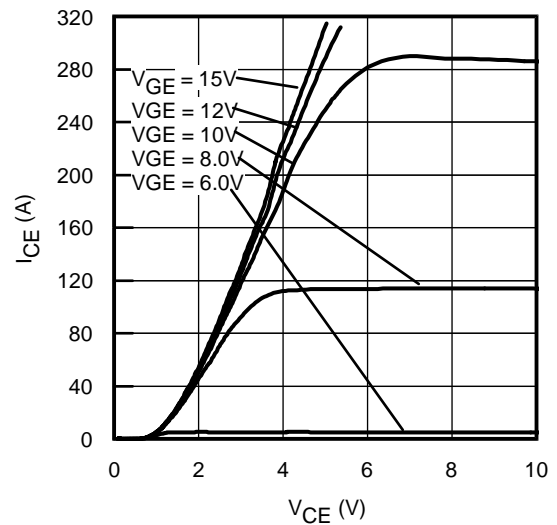


Fig. 4 - Typ. IGBT Output Characteristics
 $T_J = -40^{\circ}\text{C}$; $t_p = 80\mu\text{s}$

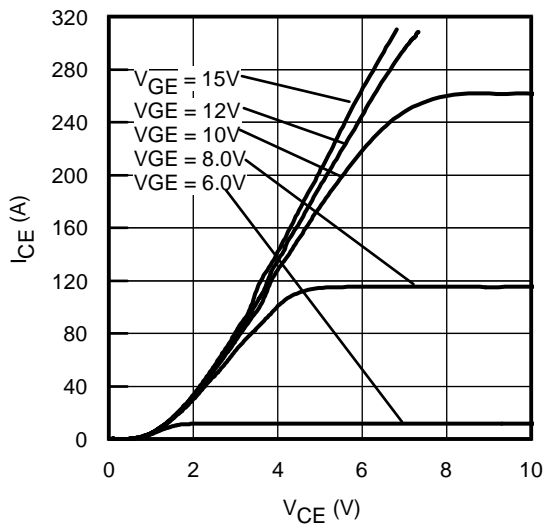


Fig. 5 - Typ. IGBT Output Characteristics
 $T_J = 25^{\circ}\text{C}$; $t_p = 80\mu\text{s}$

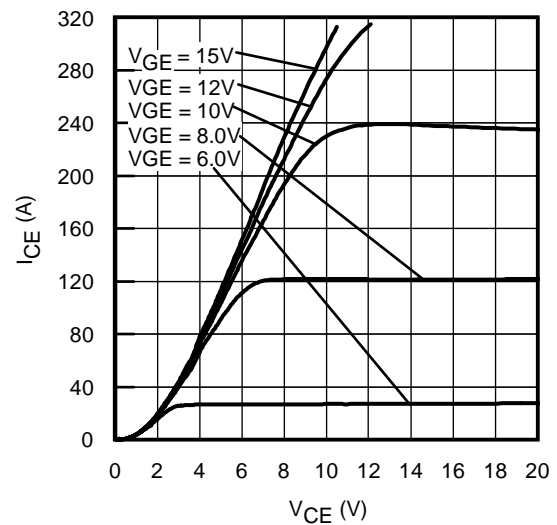


Fig. 6 - Typ. IGBT Output Characteristics
 $T_J = 125^{\circ}\text{C}$; $t_p = 80\mu\text{s}$

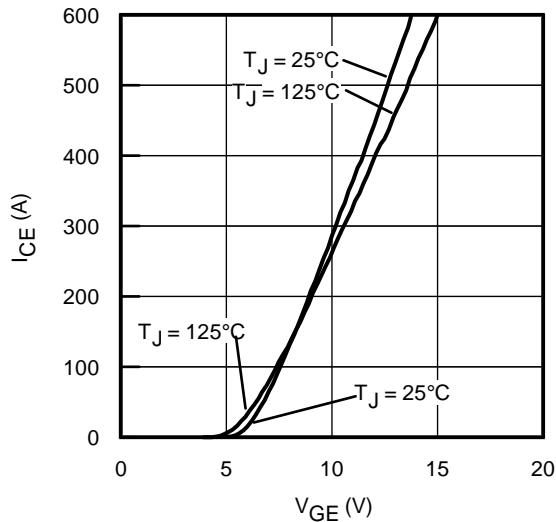


Fig. 7 - Typ. Transfer Characteristics
 $V_{CE} = 50V$; $t_p = 10\mu s$

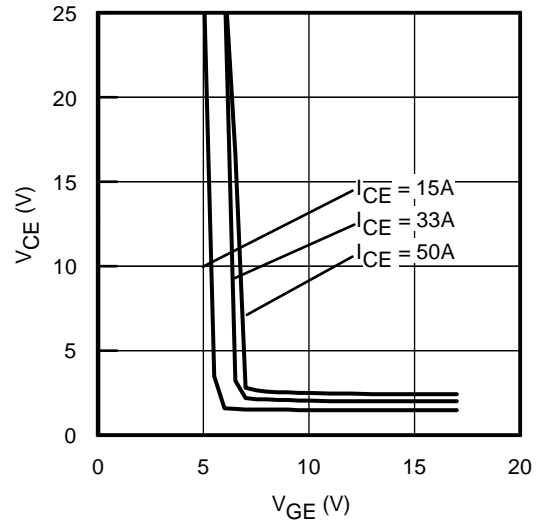


Fig. 8 - Typical V_{CE} vs. V_{GE}
 $T_J = 25^\circ C$

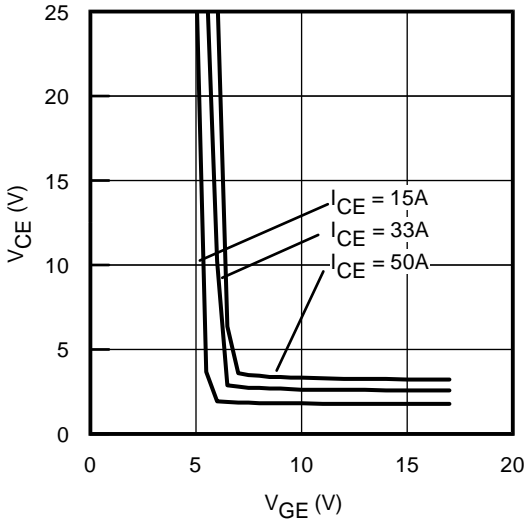


Fig. 9 - Typical V_{CE} vs. V_{GE}
 $T_J = 125^\circ C$

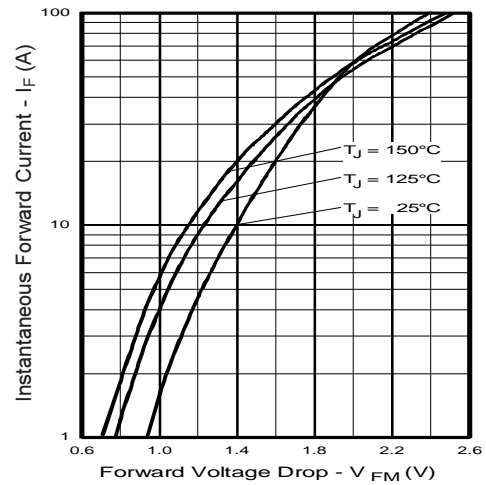


Fig. 10 - Maximum Diode Forward Characteristics
 $t_p = 80\mu s$

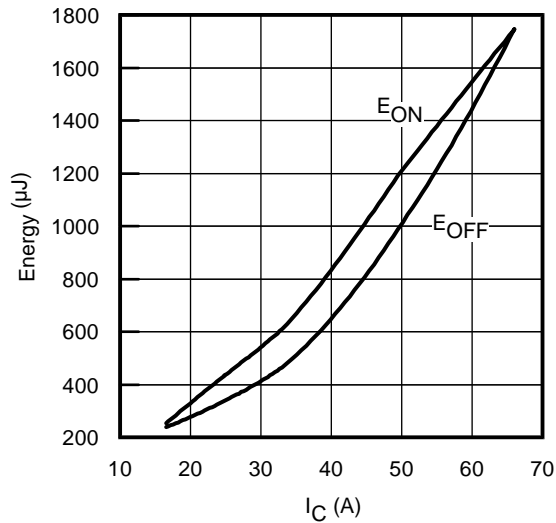


Fig. 11 - Typ. Energy Loss vs. I_C
 $T_J = 125^\circ C$; $L = 200\mu H$; $V_{CE} = 390V$; $R_G = 3.3\Omega$; $V_{GE} = 15V$.
Diode clamp used: 30ETH06 (See C.T.3)

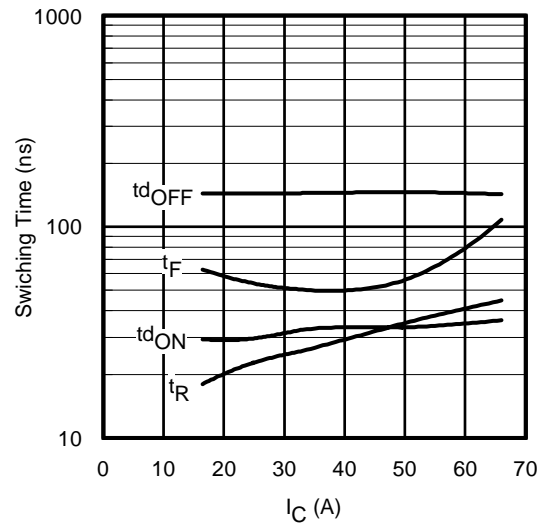


Fig. 12 - Typ. Switching Time vs. I_C
 $T_J = 125^\circ C$; $L = 200\mu H$; $V_{CE} = 390V$; $R_G = 3.3\Omega$; $V_{GE} = 15V$.
Diode clamp used: 30ETH06 (See C.T.3)

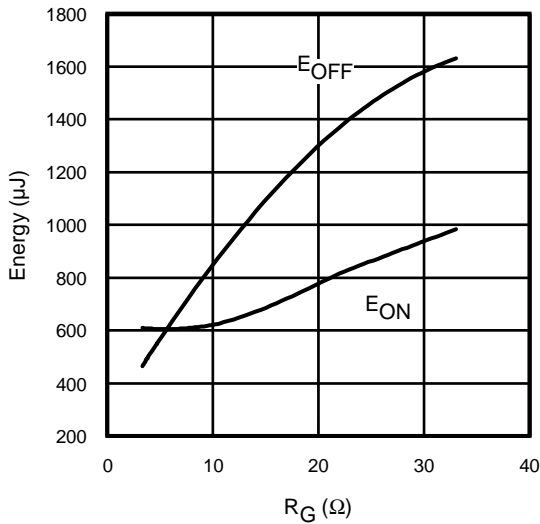


Fig. 13 - Typ. Energy Loss vs. R_G
 $T_J = 125^\circ\text{C}$; $L = 200\mu\text{H}$; $V_{CE} = 390\text{V}$; $I_{CE} = 33\text{A}$; $V_{GE} = 15\text{V}$
 Diode clamp used: 30ETH06 (See C.T.3)

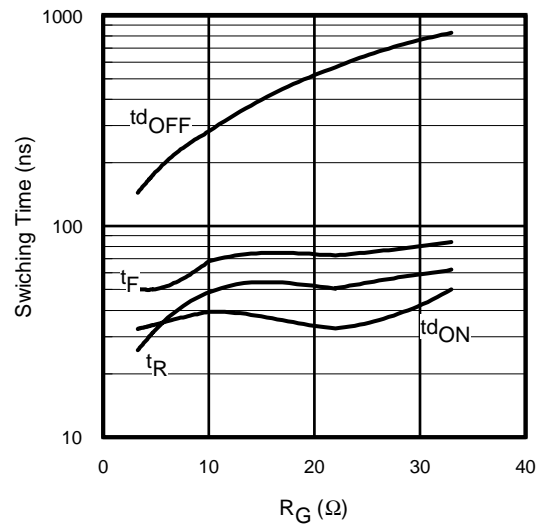
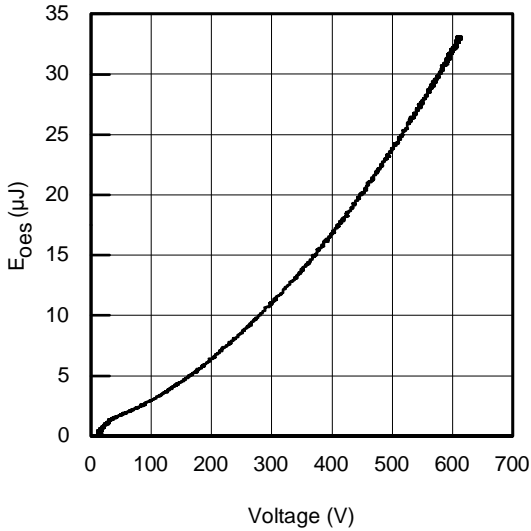


Fig. 14 - Typ. Switching Time vs. R_G
 $T_J = 125^\circ\text{C}$; $L = 200\mu\text{H}$; $V_{CE} = 390\text{V}$; $I_{CE} = 33\text{A}$; $V_{GE} = 15\text{V}$
 Diode clamp used: 30ETH06 (See C.T.3)



**Fig. 15- Typ. Output Capacitance
 Stored Energy vs. V_{CE}**

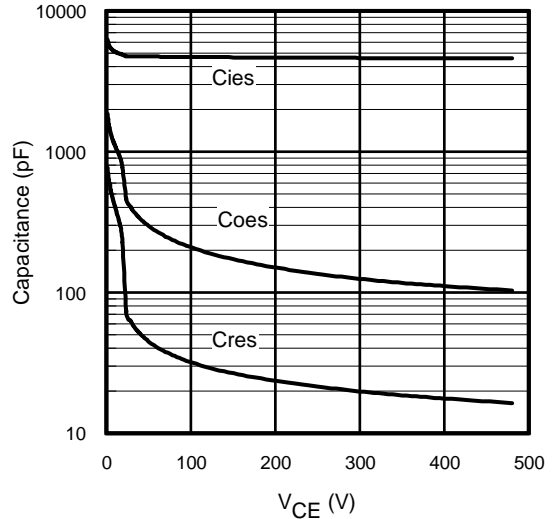


Fig. 16- Typ. Capacitance vs. V_{CE}
 $V_{GE} = 0\text{V}$; $f = 1\text{MHz}$

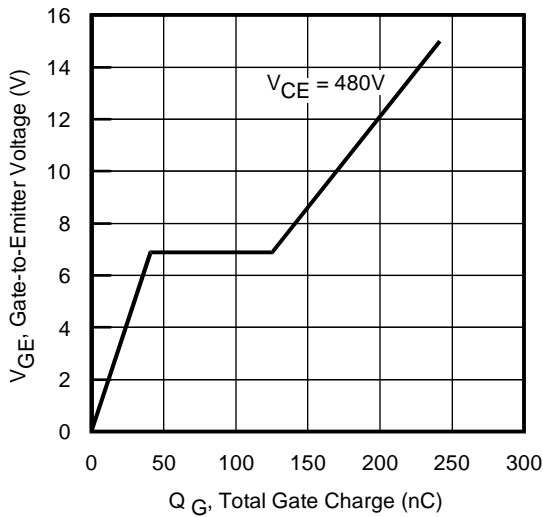
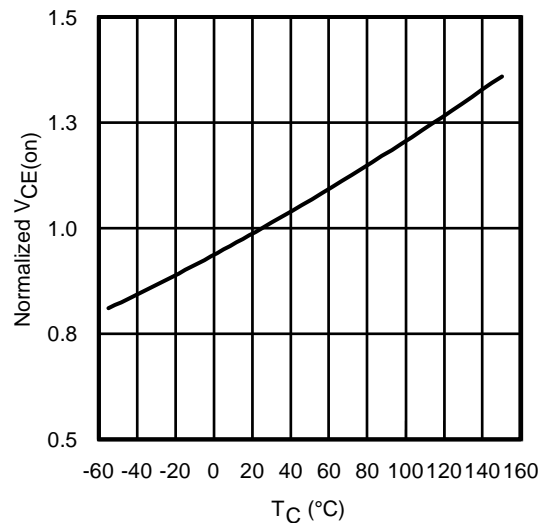


Fig. 17 - Typical Gate Charge vs. V_{GE}
 $I_{CE} = 33\text{A}$



**Fig. 18 - Normalized Typ. $V_{CE(on)}$
 vs. Junction Temperature**
 $I_C = 33\text{A}$, $V_{GE} = 15\text{V}$

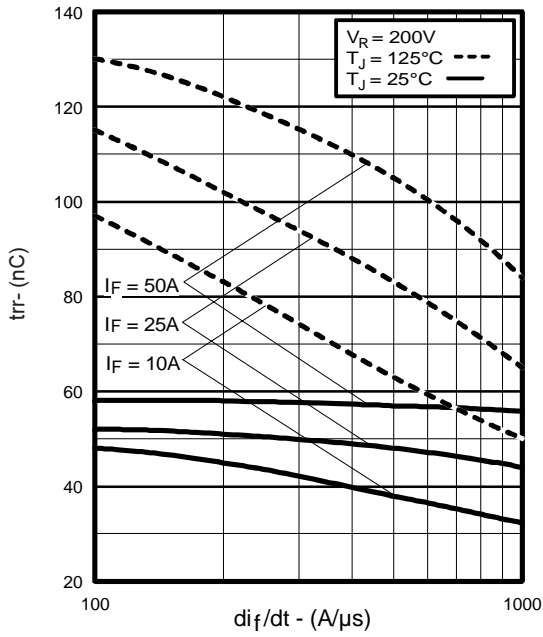


Fig. 19 - Typical Reverse Recovery vs. di_f/dt

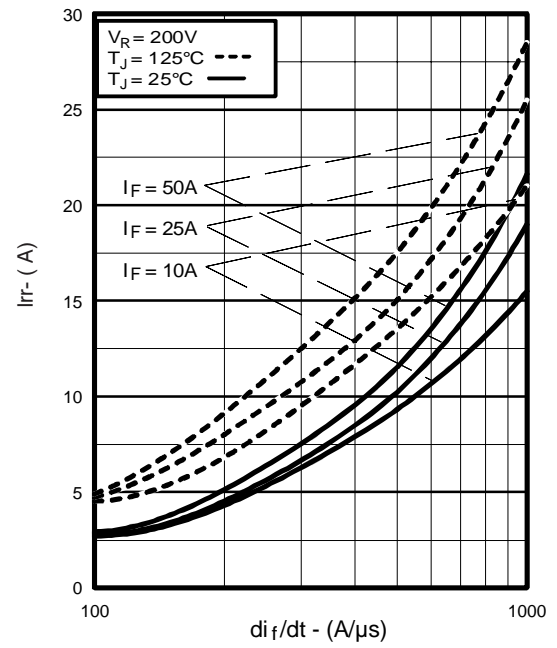


Fig. 20 - Typical Recovery Current vs. di_f/dt

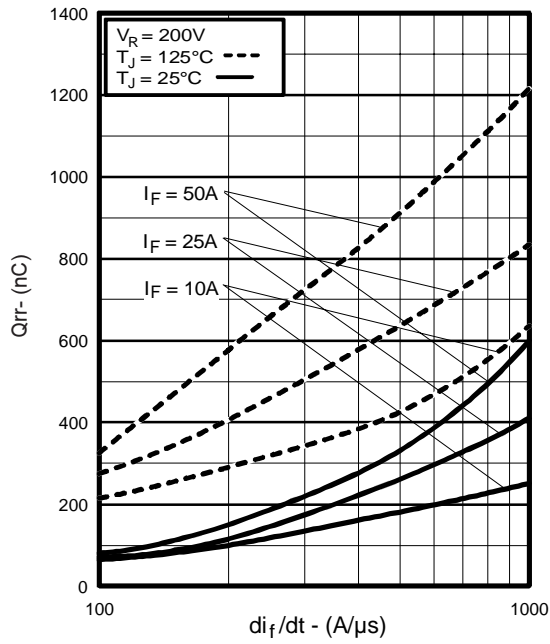


Fig. 21 - Typical Stored Charge vs. di_f/dt

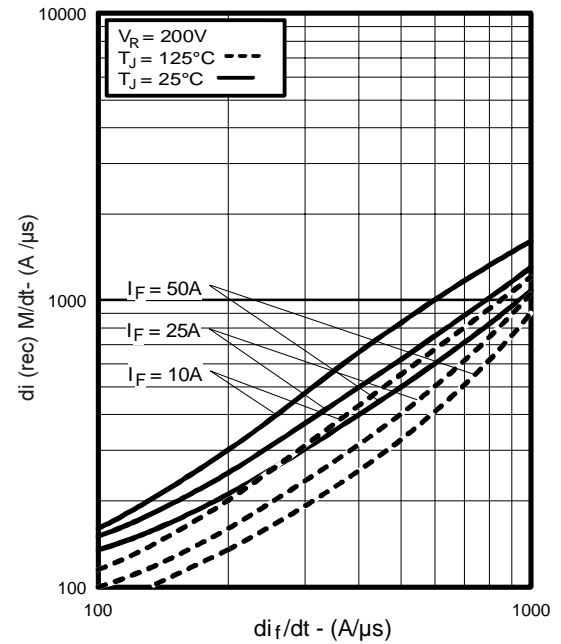


Fig. 22 - Typical $di_{(rec)M}/dt$ vs. di_f/dt

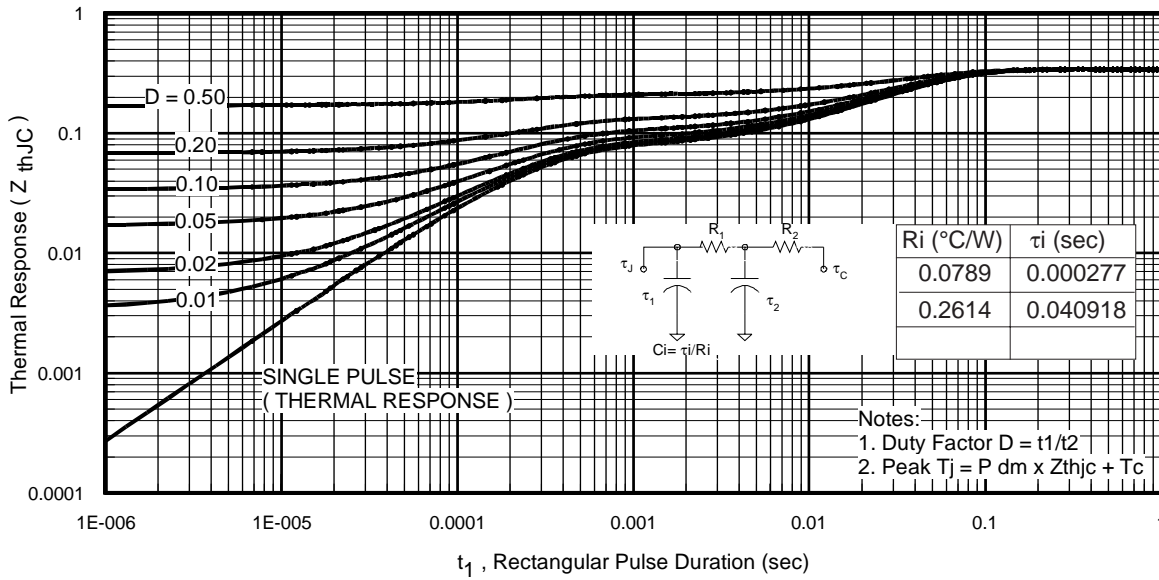


Fig 23. Maximum Transient Thermal Impedance, Junction-to-Case (IGBT)

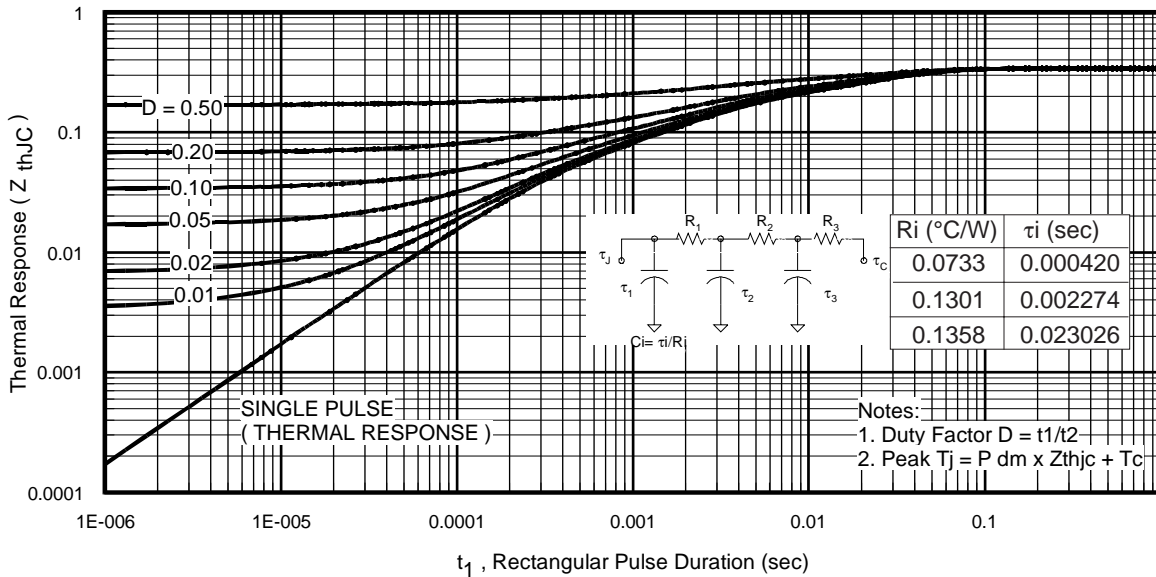


Fig. 24. Maximum Transient Thermal Impedance, Junction-to-Case (DIODE)

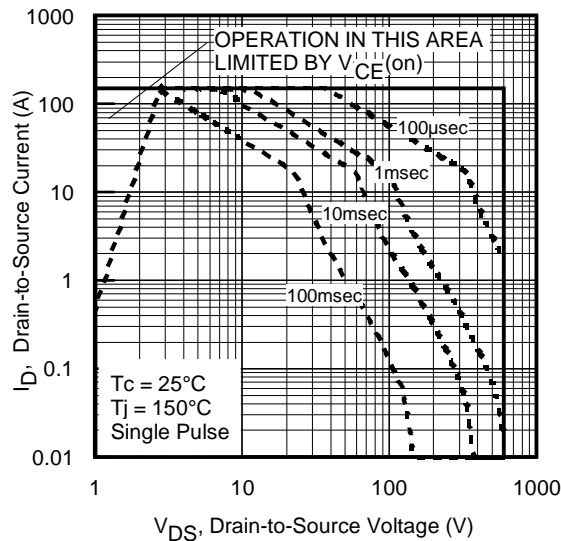


Fig. 25 - Forward SOA, $T_c = 25^\circ\text{C}$; $T_j \leq 150^\circ\text{C}$

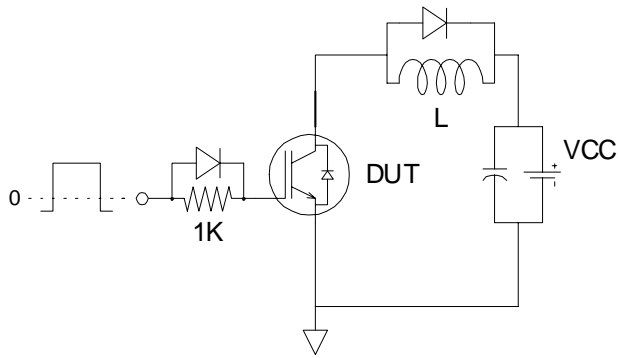


Fig.C.T.1 - Gate Charge Circuit (turn-off)

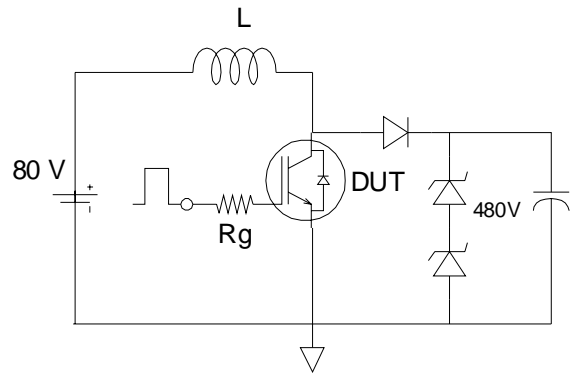


Fig.C.T.2 - RBSOA Circuit

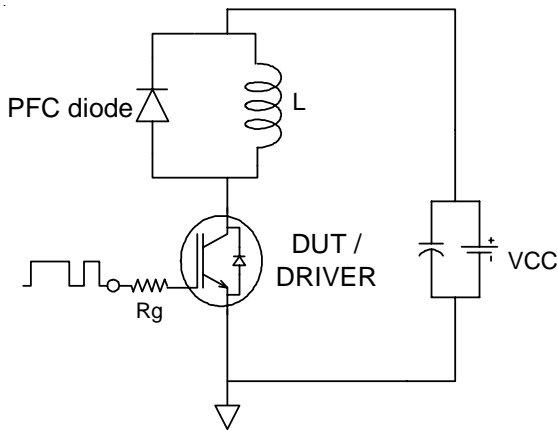


Fig.C.T.3 - Switching Loss Circuit

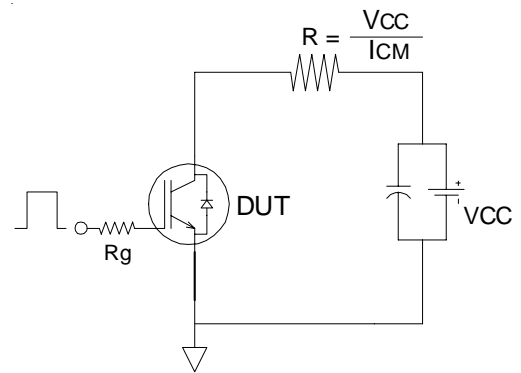


Fig.C.T.4 - Resistive Load Circuit

REVERSE RECOVERY CIRCUIT

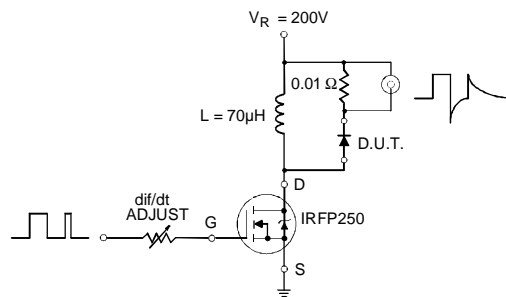


Fig. C.T.5 - Reverse Recovery Parameter Test Circuit

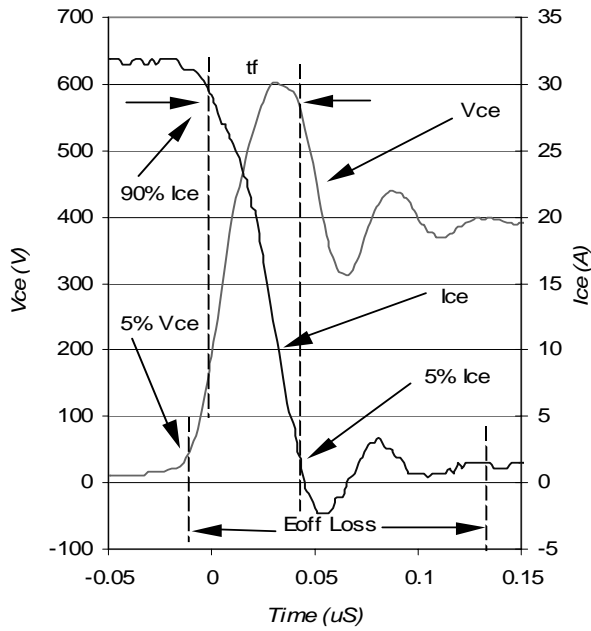


Fig. WF1 - Typ. Turn-off Loss Waveform
@ $T_J = 25^\circ\text{C}$ using Fig. CT.3

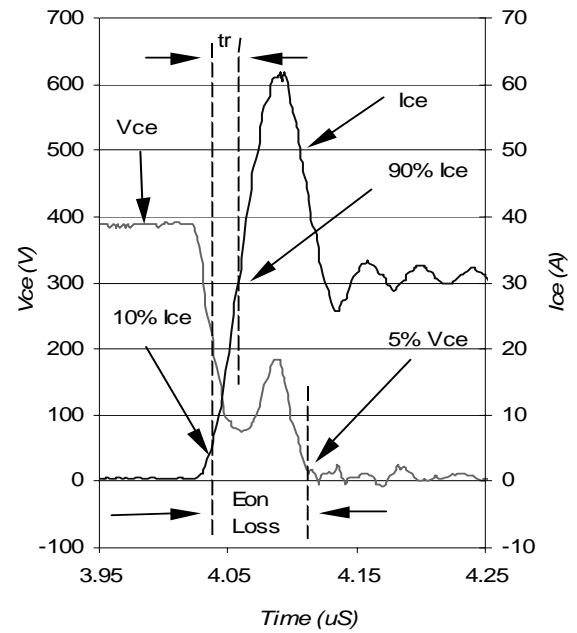
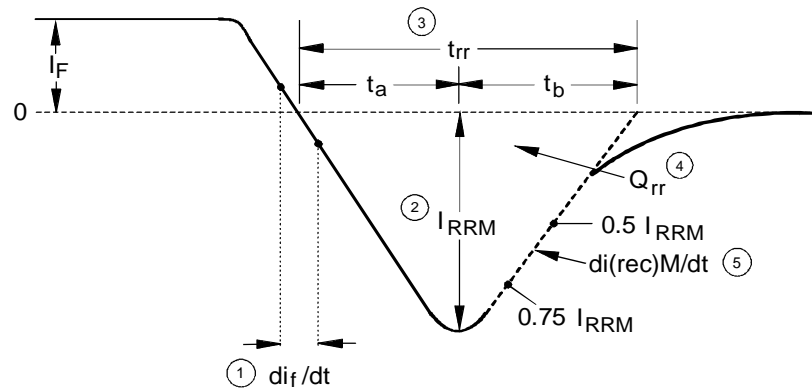


Fig. WF2 - Typ. Turn-on Loss Waveform
@ $T_J = 25^\circ\text{C}$ using Fig. CT.3



1. di_f/dt - Rate of change of current through zero crossing
2. I_{RRM} - Peak reverse recovery current
3. t_{rr} - Reverse recovery time measured from zero crossing point of negative going I_F to point where a line passing through $0.75 I_{RRM}$ and $0.50 I_{RRM}$ extrapolated to zero current
4. Q_{rr} - Area under curve defined by t_{rr} and I_{RRM}

$$Q_{rr} = \frac{t_{rr} \times I_{RRM}}{2}$$
5. $di_{(rec)M}/dt$ - Peak rate of change of current during t_b portion of t_{rr}

Fig. WF3 - Reverse Recovery Waveform and Definitions

Note: For the most current drawings please refer to the IR website at:
<http://www.irf.com/package/>